

Introduction to Nanolithography

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Outline

- Introduction
- Photolithography
- Soft Lithography
- Nanoimprint Lithography (NIL)
- NIL System Overview
- Conclusion

Nanolithography

Nanolithography is the branch of [nanotechnology](#) concerned with the study and application of fabricating nanometer-scale structures, meaning patterns with at least one lateral dimension between the size of an individual atom and approximately 100 nm.



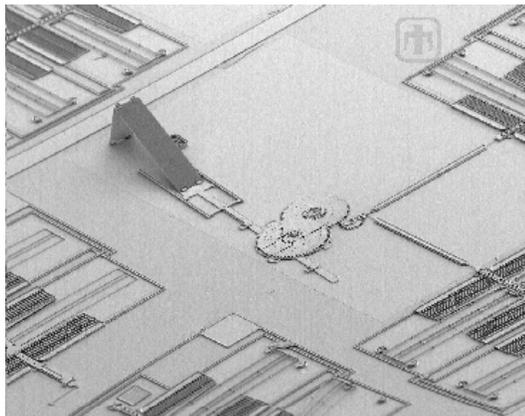
Introduction

- Why we need micro/nano pattern?

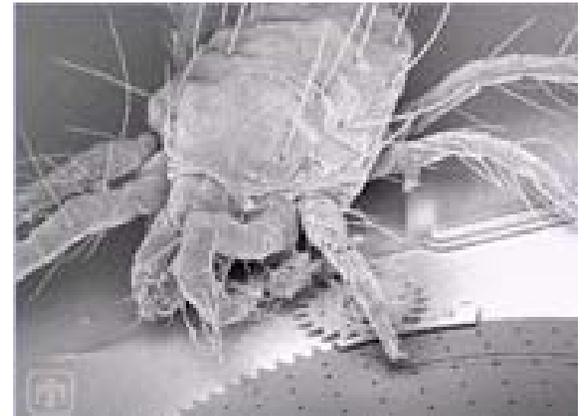
MEMS (Micro electronic mechanical system)



A MEMS device
[Sandia National Laboratories]



optical switch
(Sandia)



ratcheted microgear
(Sandia)

Top-down Versus Bottom-up

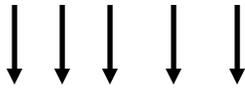
Top Down Process



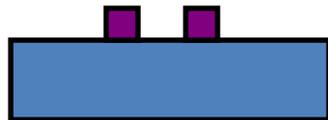
Start with bulk wafer



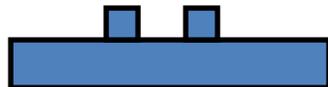
Apply layer of photoresist



Expose wafer with UV light through mask and etch wafer



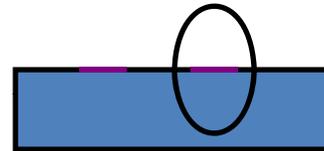
Etched wafer with desired pattern



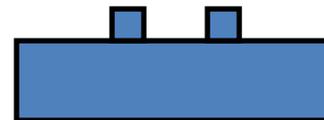
Bottom Up Process



Start with bulk wafer



Alter area of wafer where structure is to be created by adding polymer or seed crystals or other techniques.

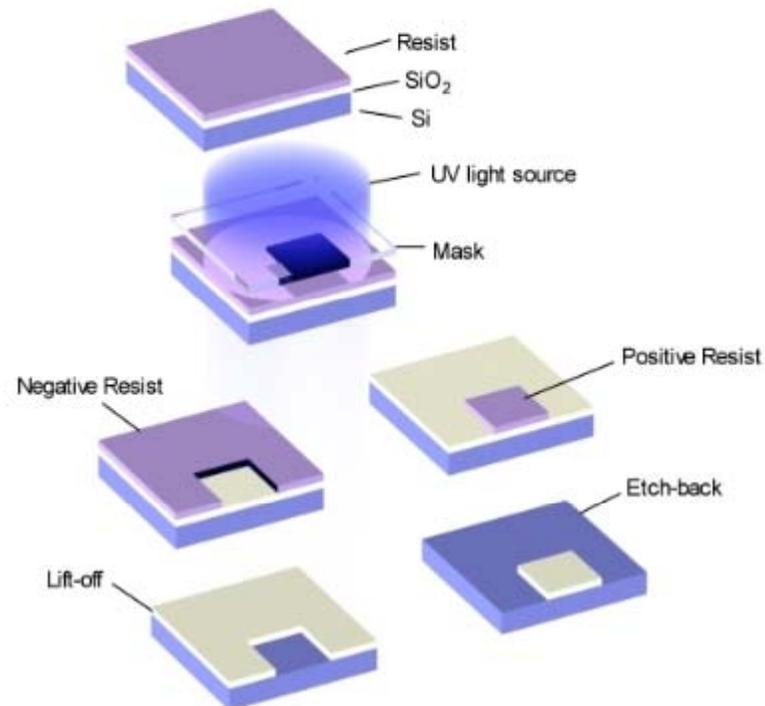


Grow or assemble the structure on the area determined by the seed crystals or polymer. (self assembly)

Similar results can be obtained through bottom-up and top-down processes

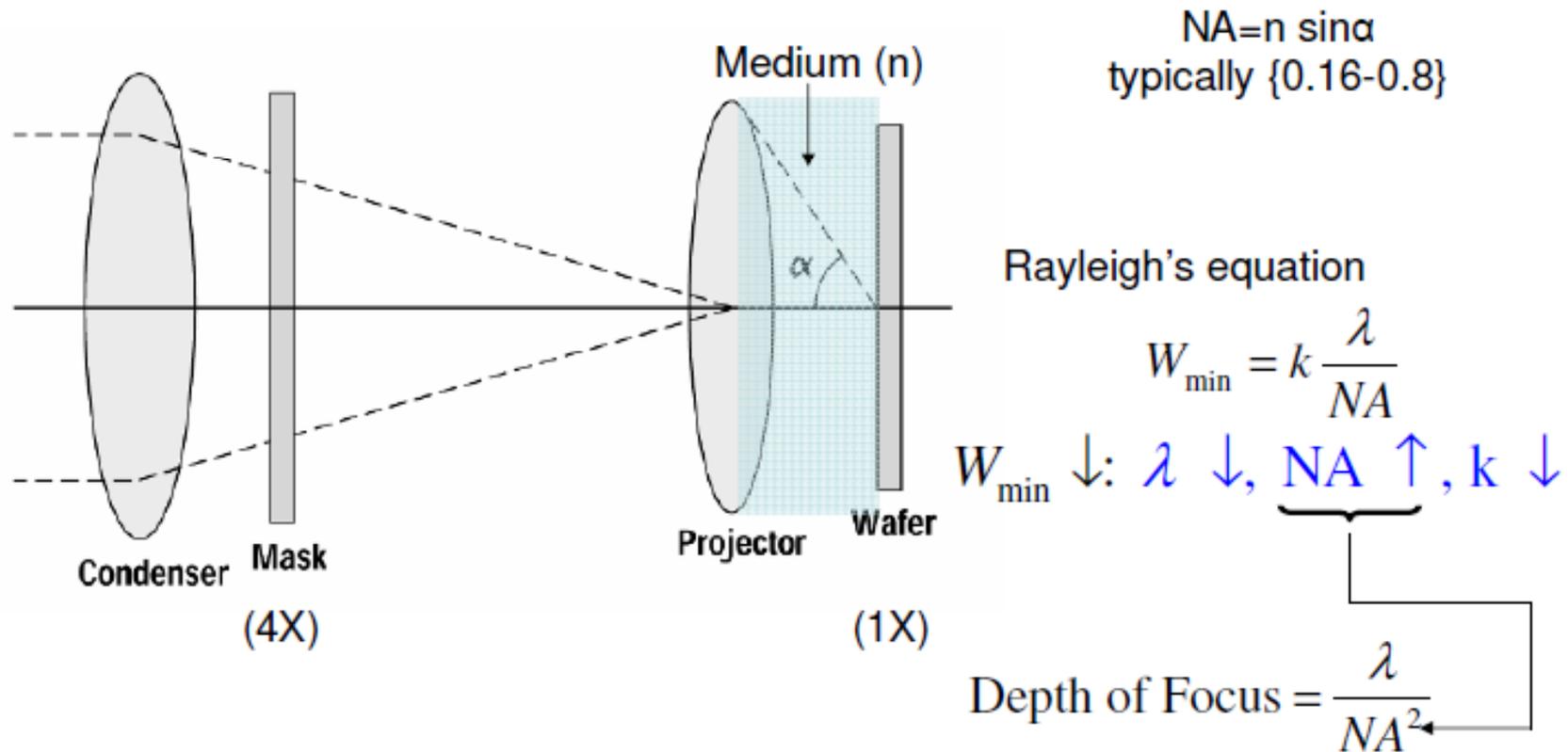
Photolithography

<https://www.youtube.com/watch?v=1bxf9QRVesQ>



Optical Projection Printers

- Most widely used litho for IC manufacturing

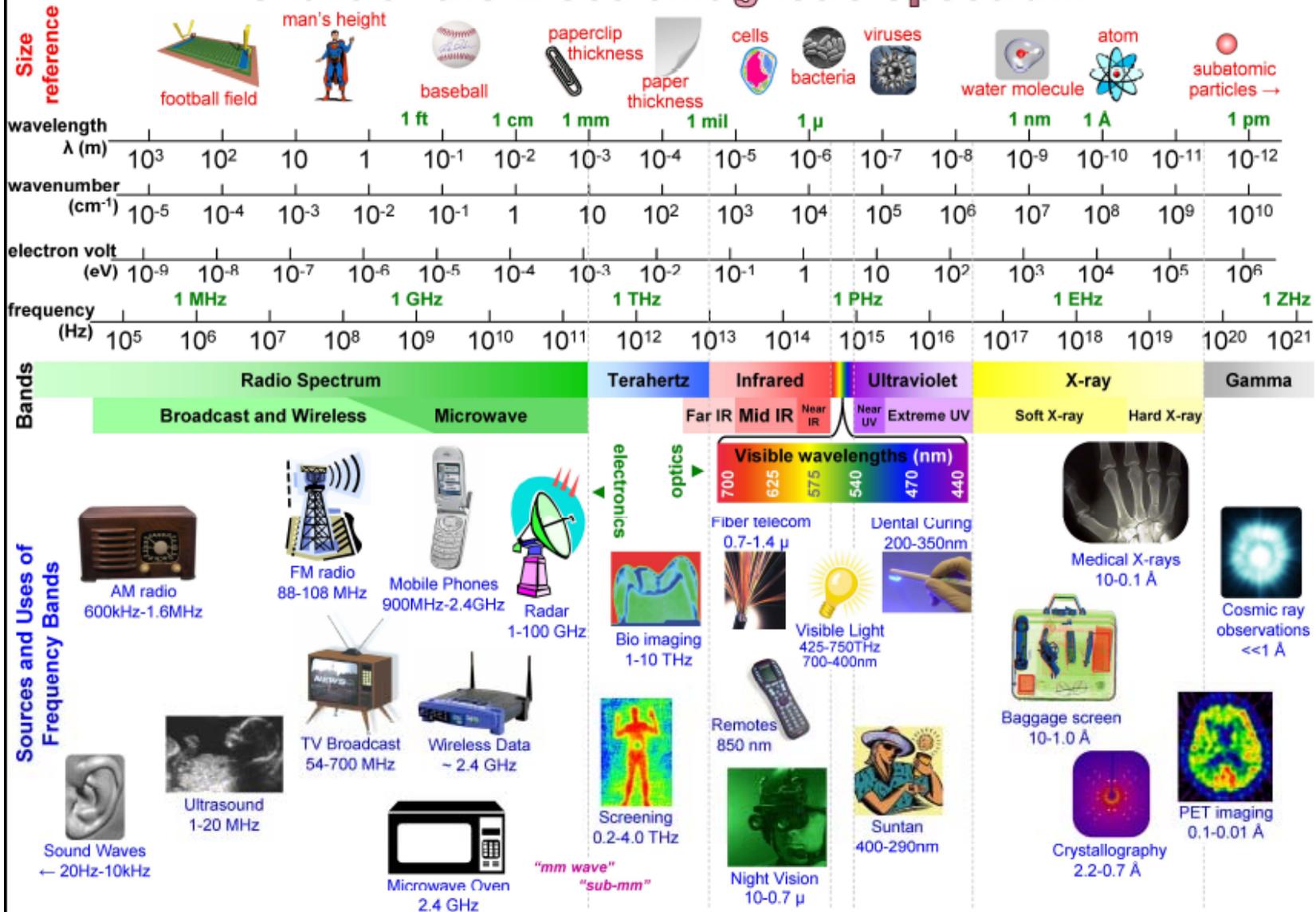


- The resolution of optical projection lithography is limited by diffraction as described by the Rayleigh eqn
- k is function of resist & 'optical engineering' (OPC, PSM)

*S. Campbell, The Science and Engineering of Microelectronic Fabrication, 2nd Ed.

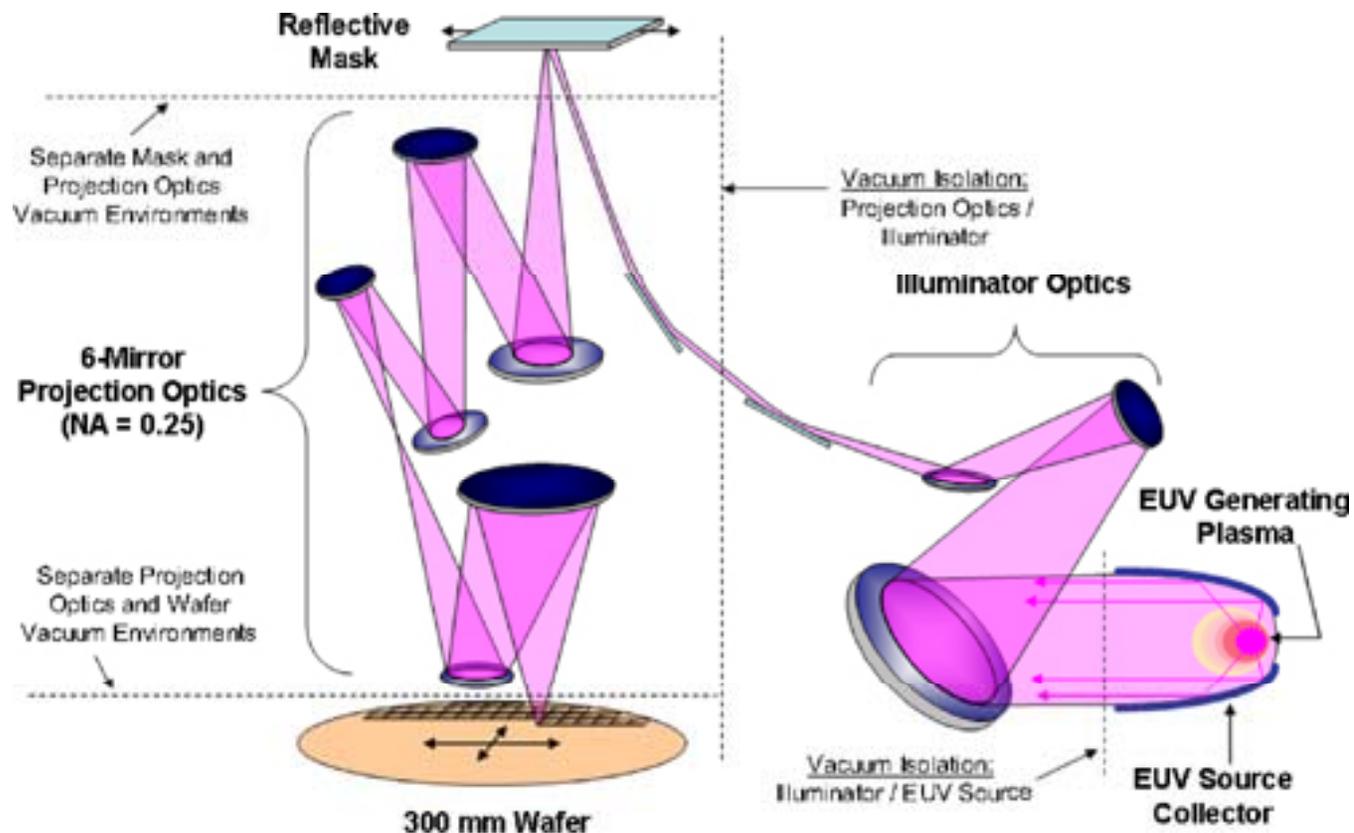
*ITRS, 2005

Chart of the Electromagnetic Spectrum



EUV lithography

- **Extreme ultraviolet lithography** (also known as *EUV* or *EUVL*) is a [next-generation lithography](#) technology using an [EUV](#) wavelength, currently expected to be 13.5 nm.



Photolithography Limits

- It requires expensive instruments and facilities with high capital investment
- Pattern resolution is limited by optical diffraction
- The methods is not suitable for patterning all types of polymers, and only photosensitive resist materials can be directly patterned.
- The technique requires harsh processing conditions. (Limited application for sensitive materials such as biological samples with living cell)

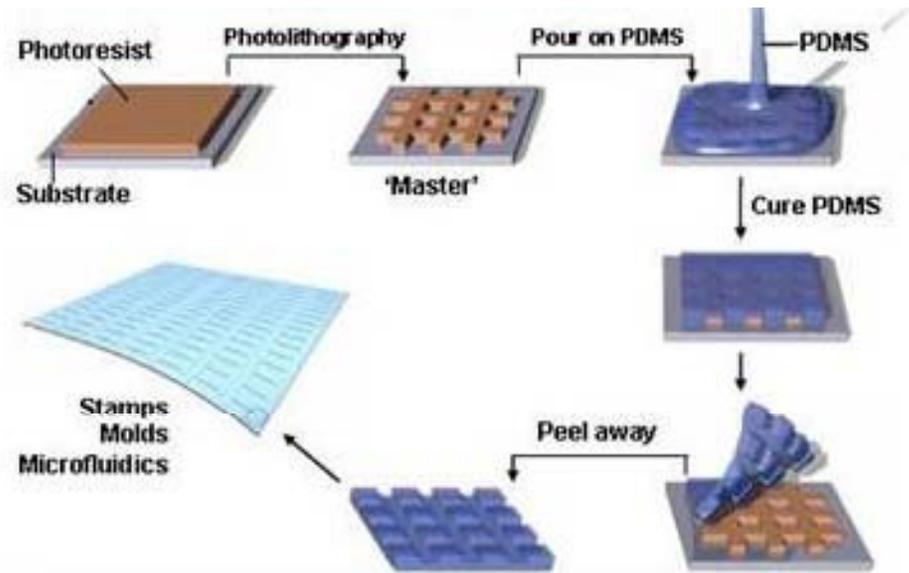
Soft Lithography

- Introduction



George Whitesides

*Department of Chemistry and Chemical Biology,
Harvard University*



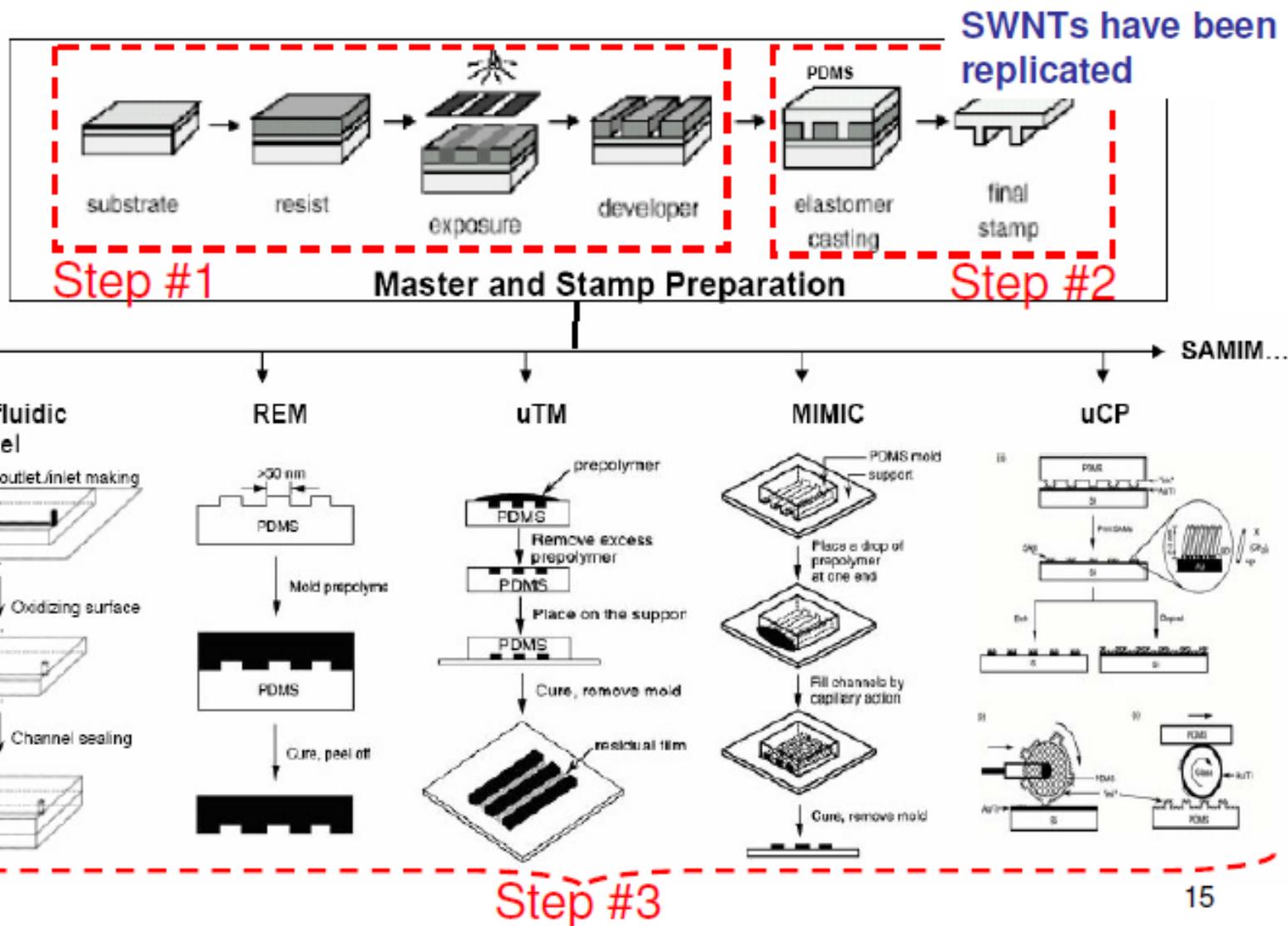
- PDMS

Soft Lithography

There are 3 basic steps in Soft Lithography:

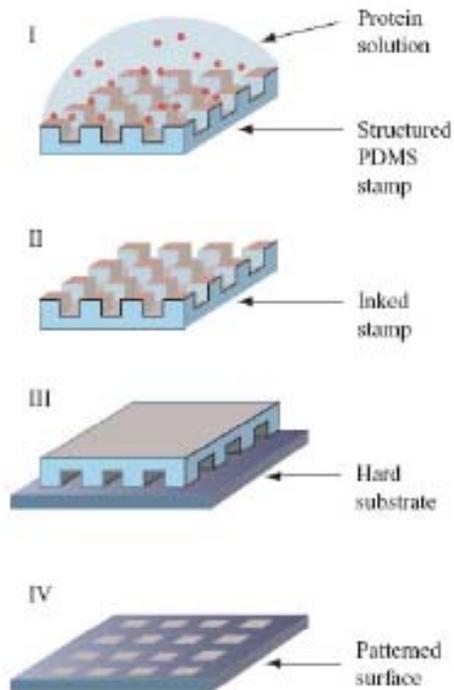
- **Step # 1:**
 - Master fabrication (usually Si wafer with SU-8 pattern) & silanize
- **Step # 2:**
 - Create PDMS micromold from the master
- **Step # 3:** use the PDMS micromold in a number of ways ...
 - Microfluidic Device Fabrication
 - Microcontact Printing (μ CP)
 - Microtransfer Molding (μ TM)
 - Micromolding in Capillaries (MIMIC)
 - Replica Molding (REM)
 - Sub-micron Soft Lithography
 - Etc.

Soft Lithography Techniques

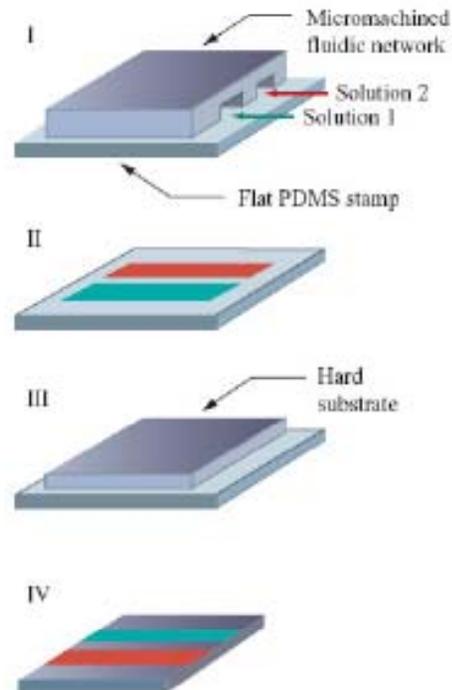
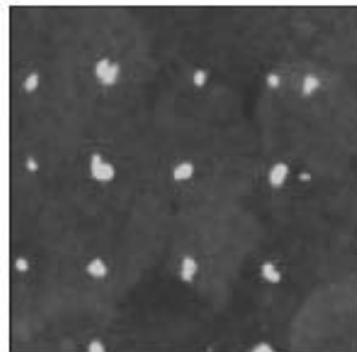


Images courtesy of D. Qin, Univ. of Washington

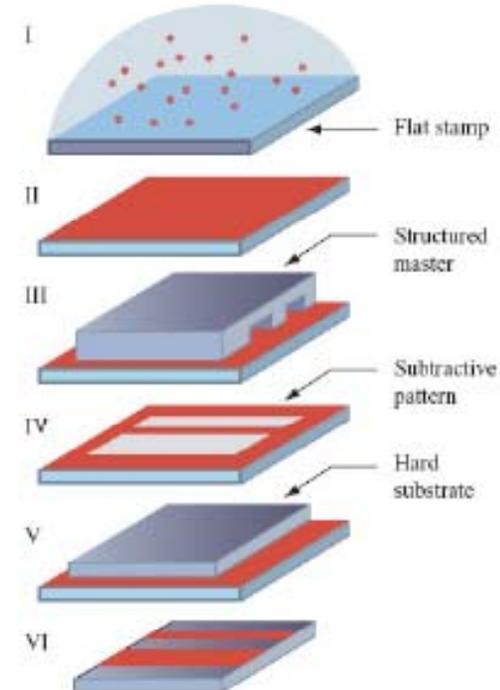
Printing of Biological Molecules (Proteins)



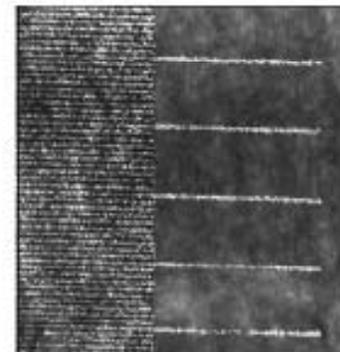
400 nm



40 μm

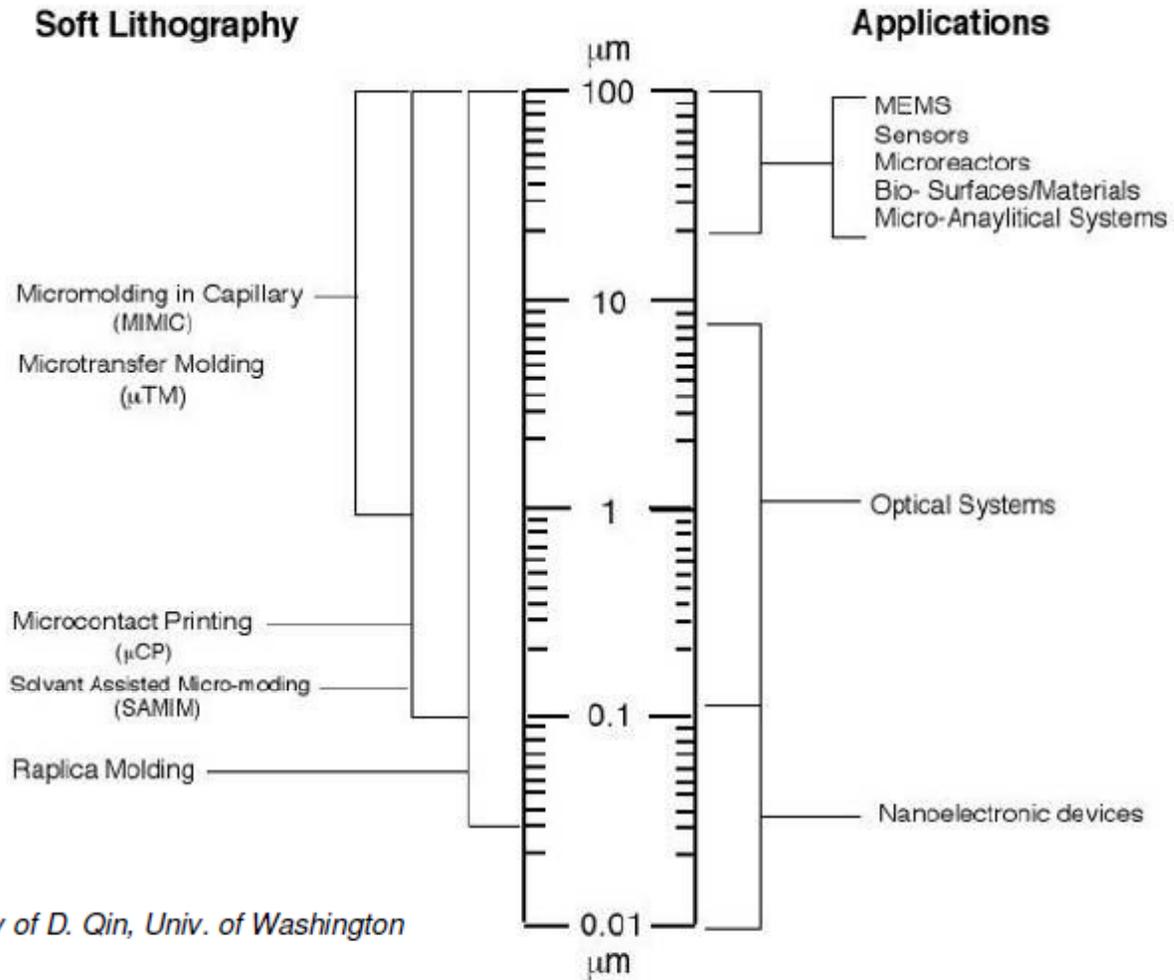


4 μm



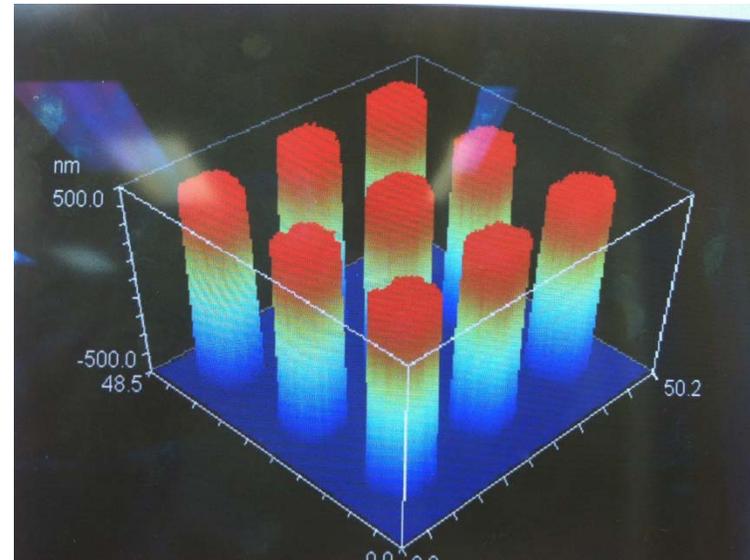
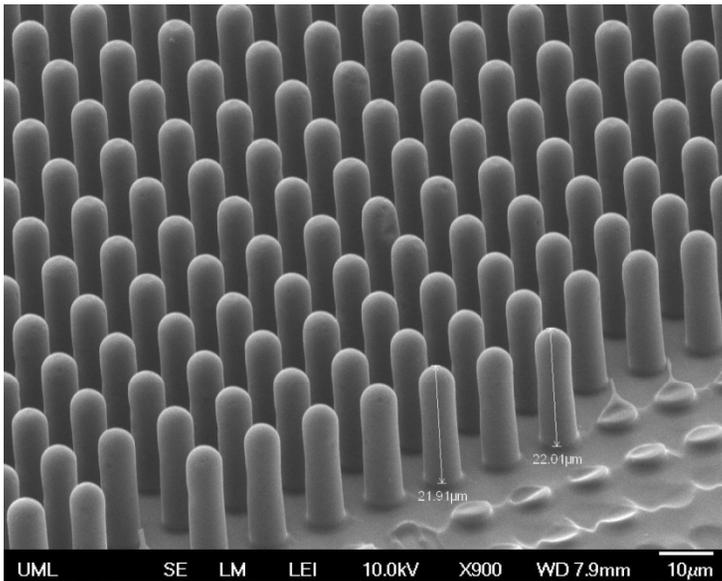
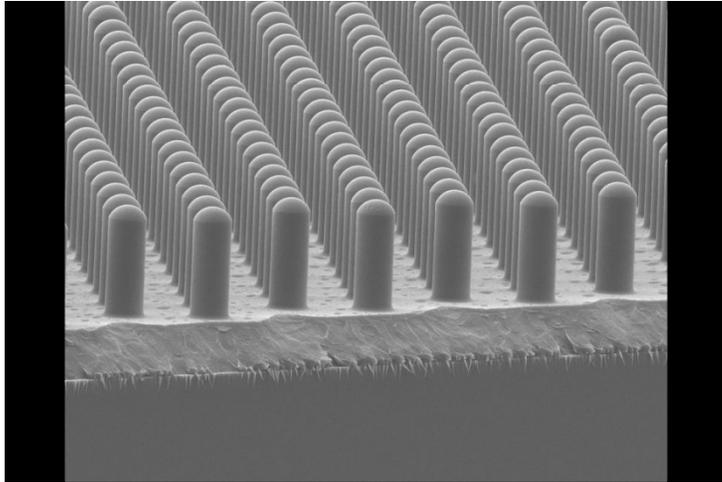
B. Michel *et al.*, *IBM J. Res. & Dev.* 2001

Soft Lithography

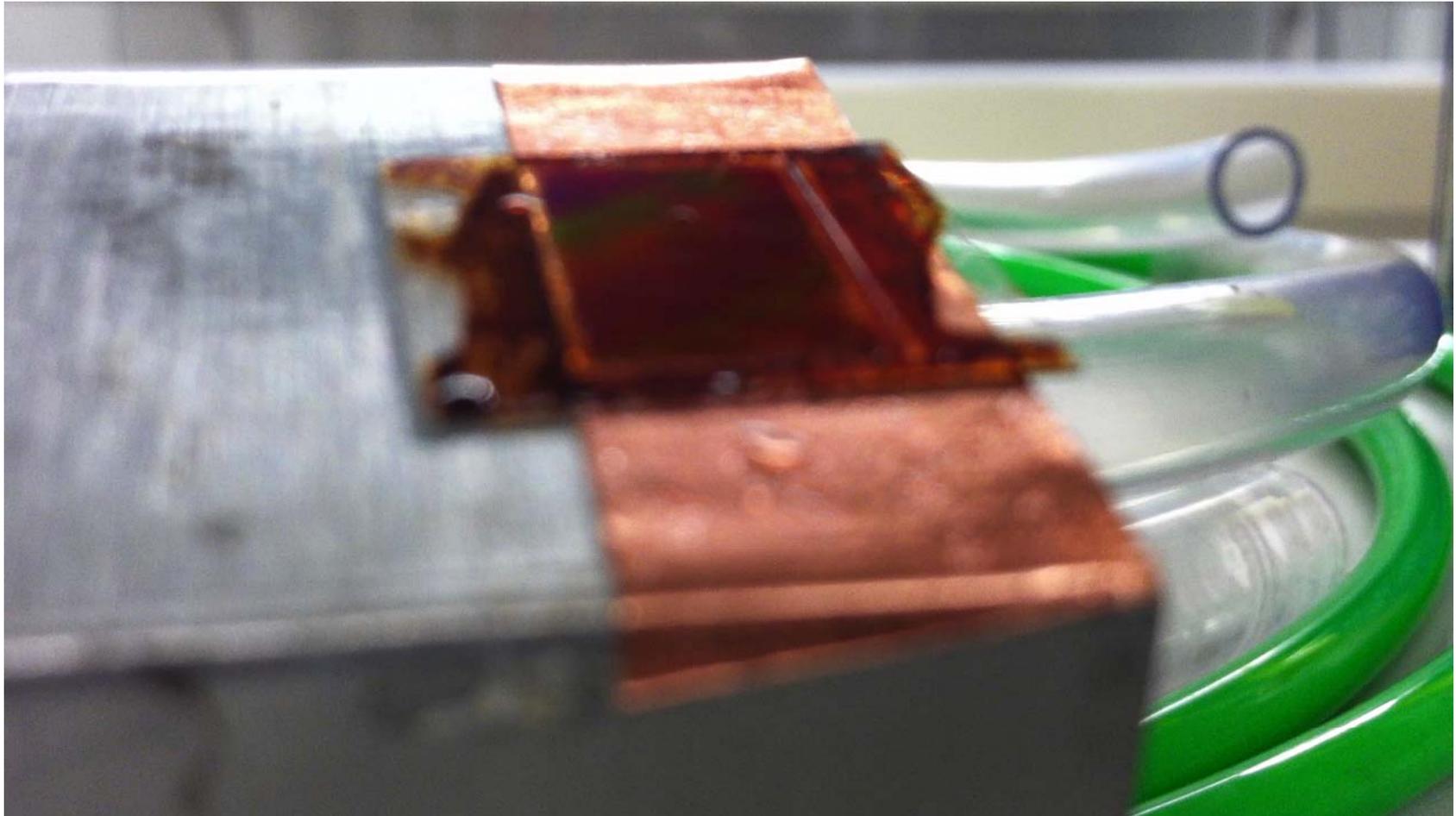


Slide courtesy of D. Qin, Univ. of Washington

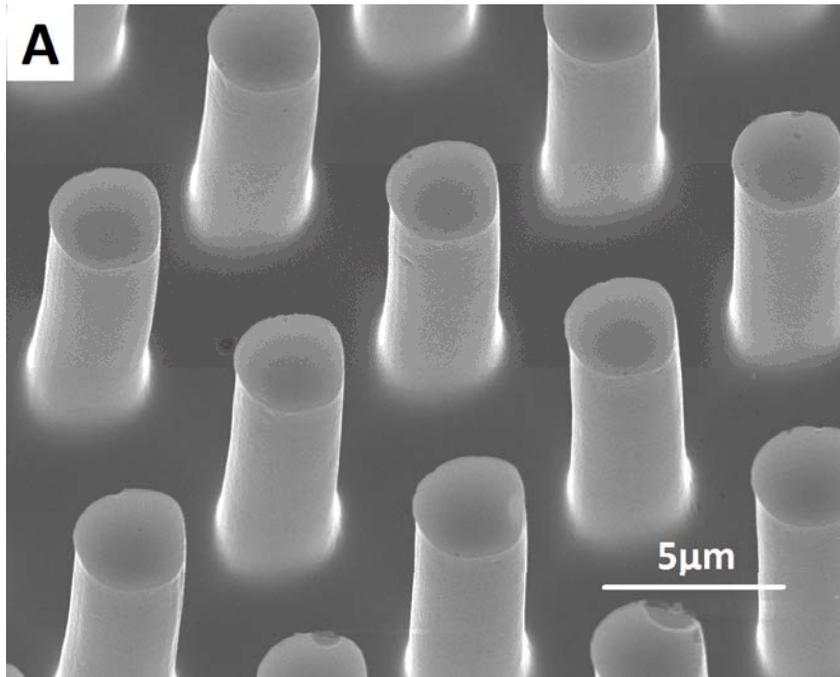
Soft Lithography Application (Superhydrophobic Surface)



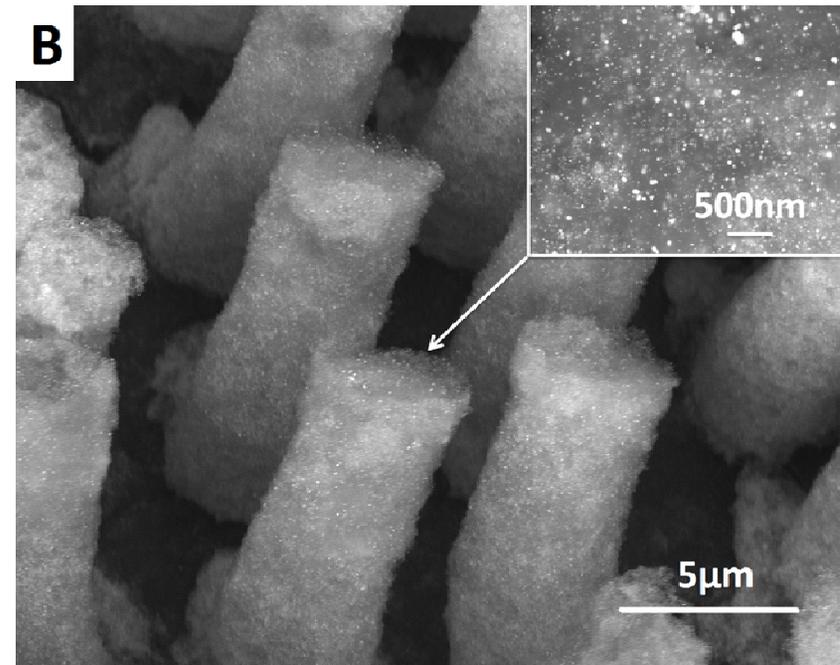
Soft Lithography Application (Superhydrophobic Surface)



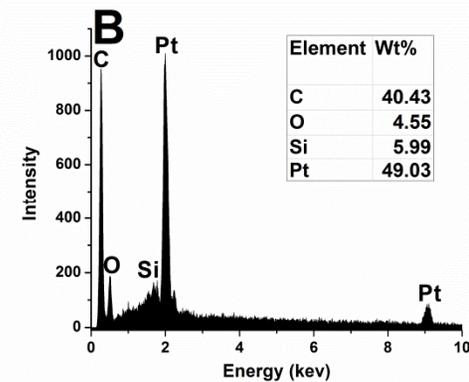
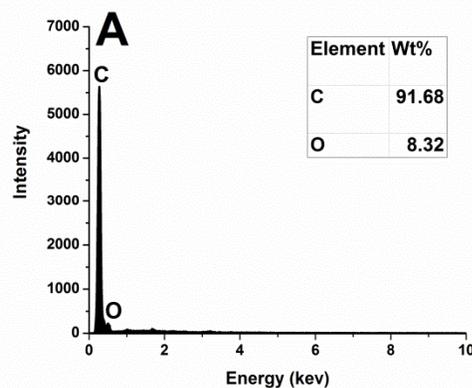
Soft Lithography Application (Carbon based MEMS-Bio Sensor)



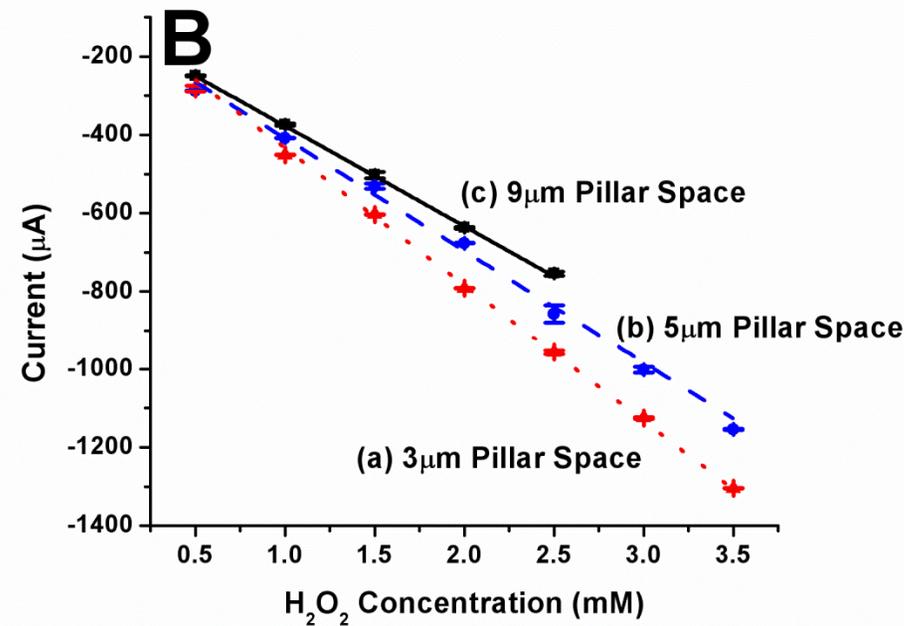
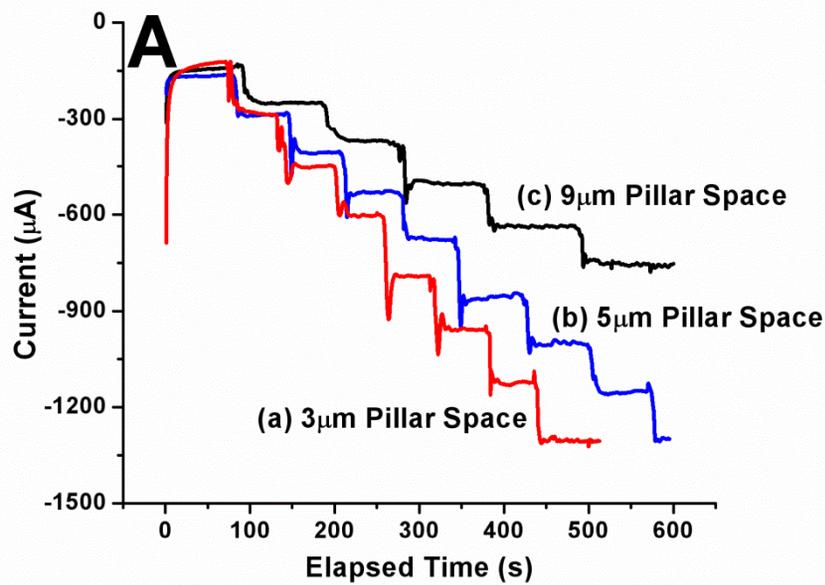
Bare Micro Carbon Pillars



Pt NPs decorated Micro Carbon Pillars



Soft Lithography Application (Carbon based MEMS-Bio Sensor)



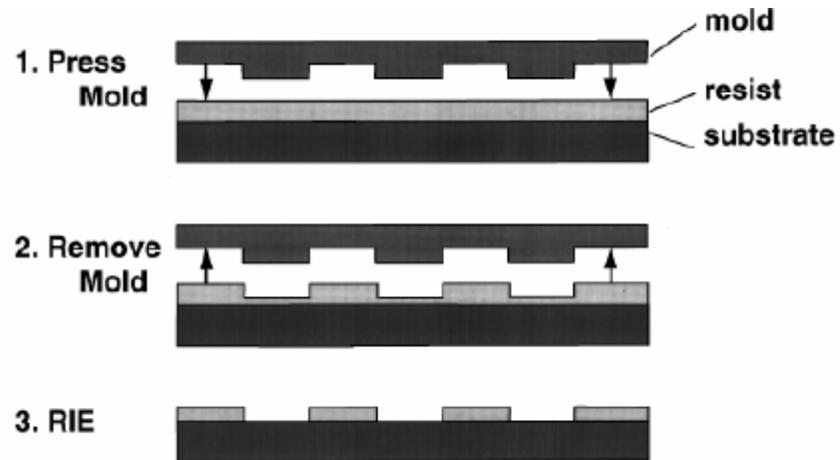
Nanoimprint Lithography (NIL)

- Introduction



Stephen Y. Chou

*the head of the NanoStructure Laboratory
Princeton University*

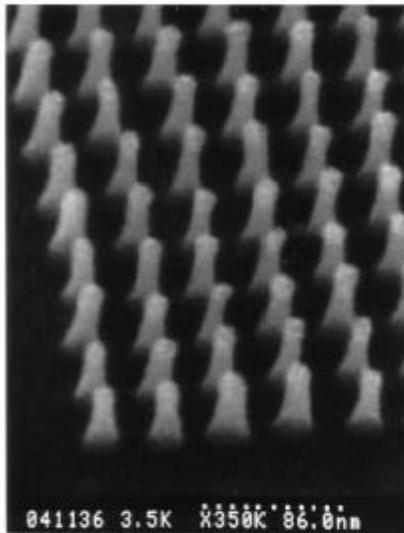


- *Hard mold (“mask”) with surface relief pattern used to emboss resist*
- *Heat and pressure are typically used during imprinting*
- *The mold is removed after imprint*
- *Resist residual layer (dry) etched to leave behind fully patterned resist*

S. Chou et al., “Nanoimprint Lithography,” J. Vac. Sci. Technol. B, 14 (6), 1996

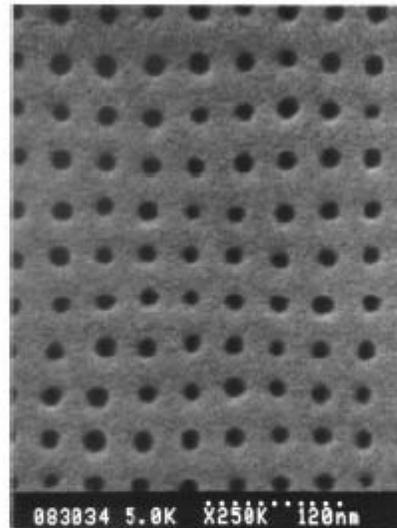
Nanoimprint Lithography (NIL)

Mold



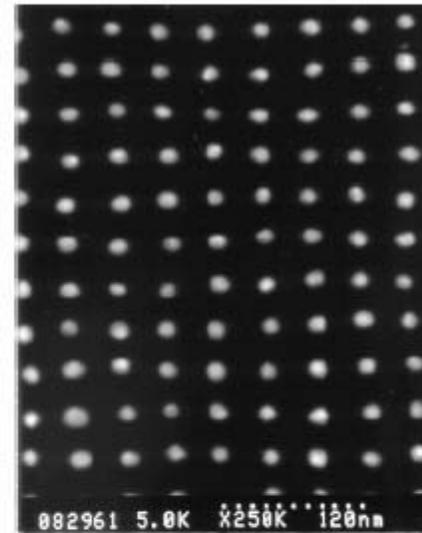
10 nm dia pillar mold

Resist



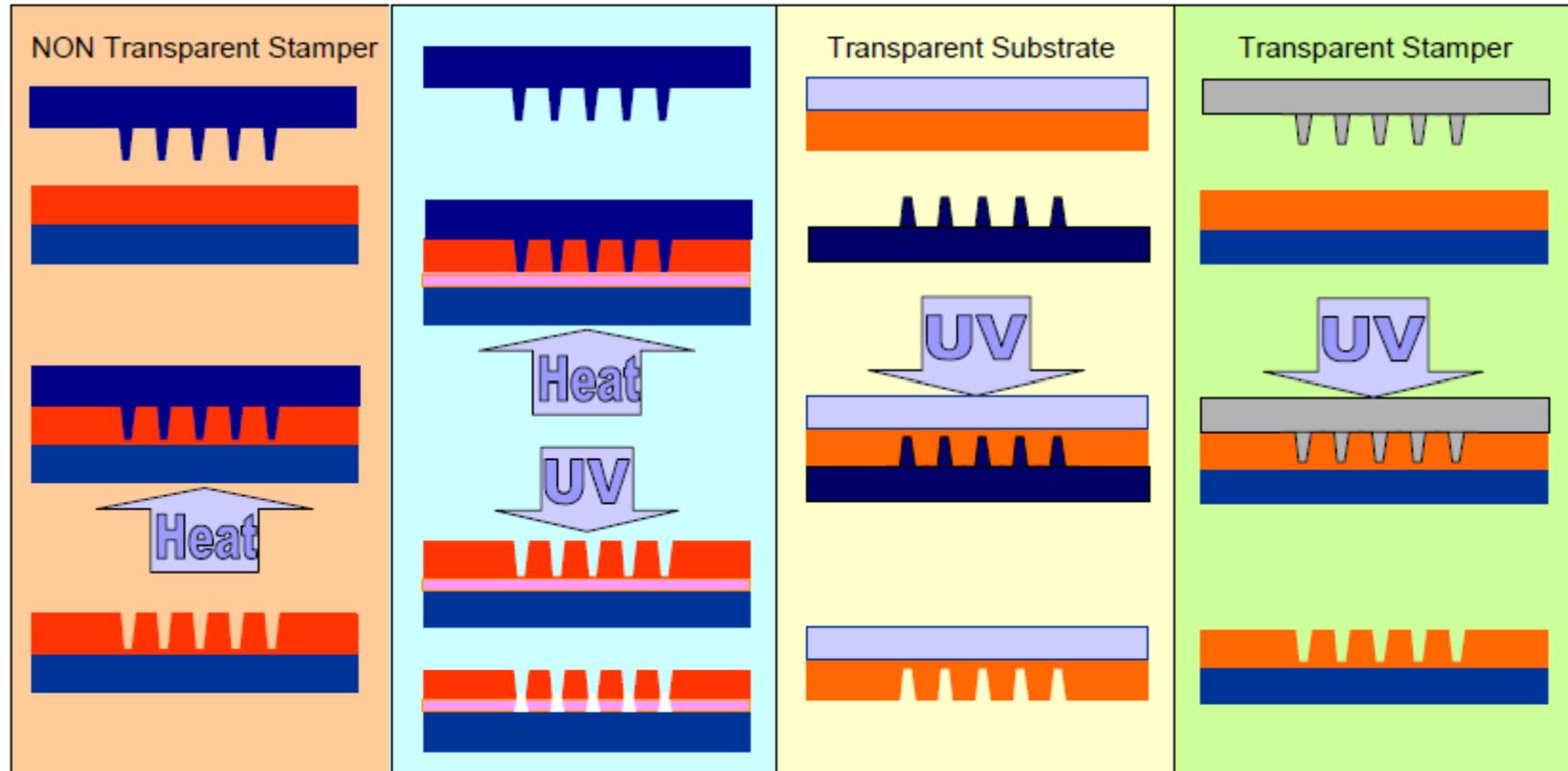
10 nm dia resist holes
by imprinting

Lift-Off



10 nm dia metal dots
by imprint and lift-off

NIL category



Thermal Imprint

(PMMA)

Thermal + UV Imprint

(SU-8)

UV Imprint

(PU)

UV Imprint

(PU)

Thermal Vs. UV NIL

Thermal:

- + Less restrictions on template
 - Si and Ni are okay
- + Simpler/cleaner process
 - UV resists are little 'messy'
- + More readily available poly/resists

- Temperature (but, controllable)
 - May be as high as 200 C
 - CTE mismatch b/w template/wfr
 - distortion of alignment: function of substrate size
- May require large force
 - Another source of distortion
 - Breakage

UV:

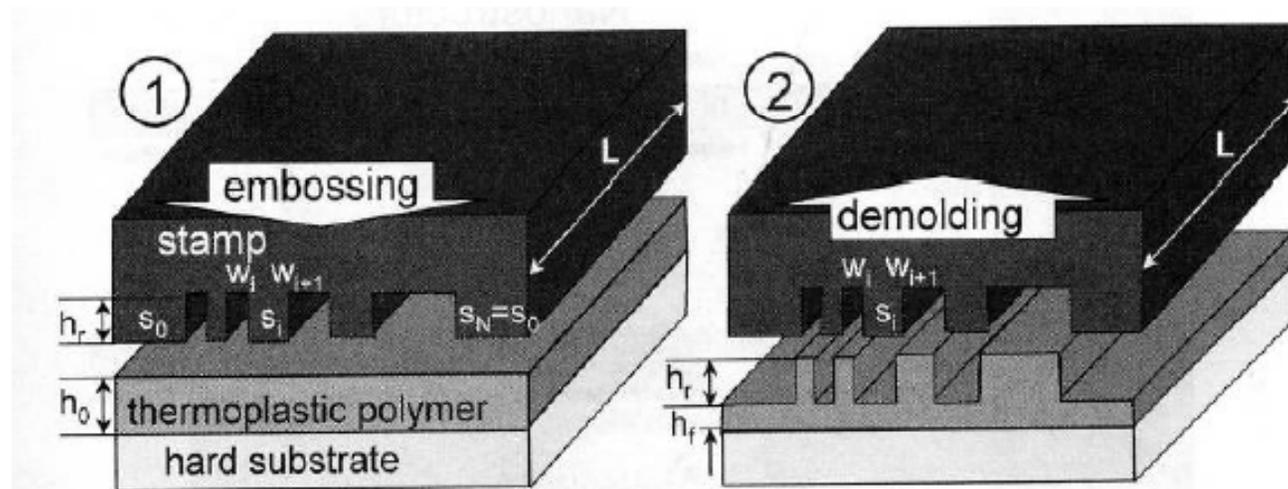
- + No thermal cycling
 - No CTE mismatch issues
- + Fast (few seconds – not including dispensing for S&F)
- + Usually minimal force needed

- volume shrinkage due to phase transition
- Uniform layers from spin coating
- Must use transparent template

Resist Polymer Available in Umass Lowell

- PMMA: $T_g=100C$, Low etch selectivity over SiO_2
- SU-8
- PU (Polyurethane)

How Much Initial Material (Resist) is Needed?



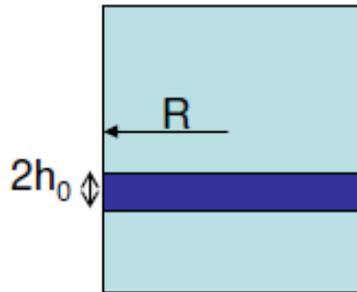
$$h_0 \sum_{i=1}^N (s_i + w_i) = h_f \sum_{i=1}^N (s_i + w_i) + h_r \sum_{i=1}^N w_i$$

$$h_0 = h_f + \frac{h_r}{\sum_{i=1}^N (s_i + w_i)} \sum_{i=1}^N w_i$$

*C. Torres, Editor, *Alternative Lithography: Unleashing the Potentials of Nanotechnology*, Kluwer, 2003

Newtonian Liquid between Two Parallel Disks

Steady-state solution to the Stefan eq:



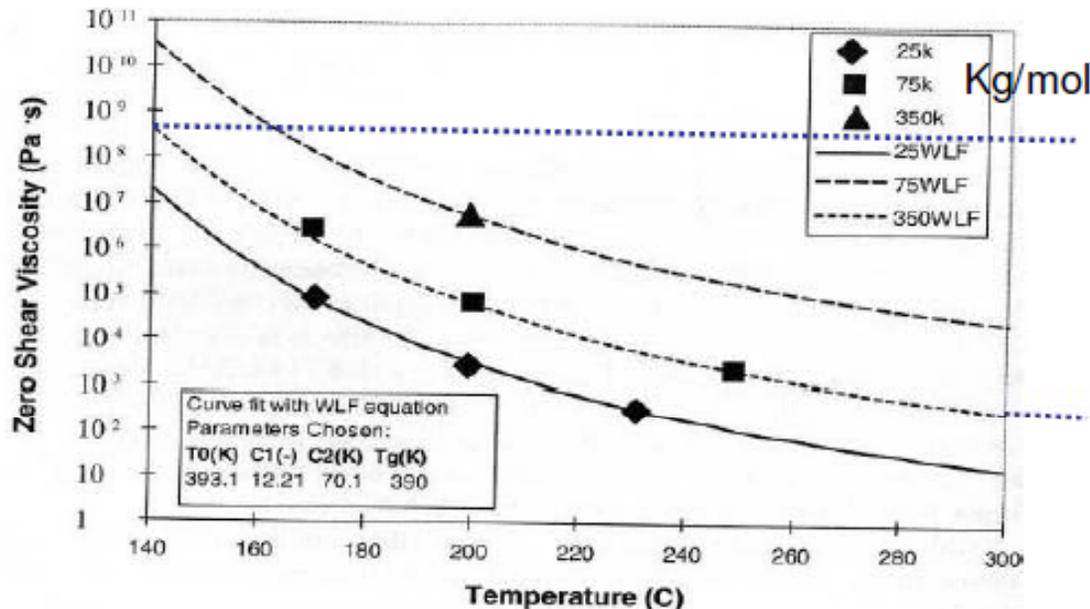
$$F = -\frac{3\pi R^4}{4h_0^3} \frac{dh}{dt} \eta_0$$

$$F \propto R^4$$

$$F \propto \frac{1}{h_0^3}$$

$$F \propto \eta_0$$

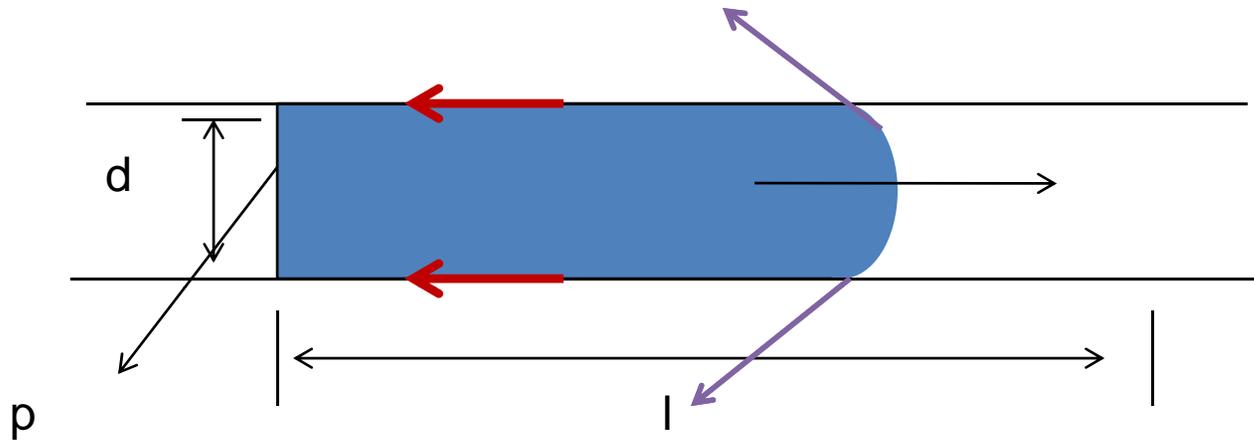
Changes by orders of magnitude with temp



Shear viscosity also function of shear velocity in (realist) materials of interest (PMMA)

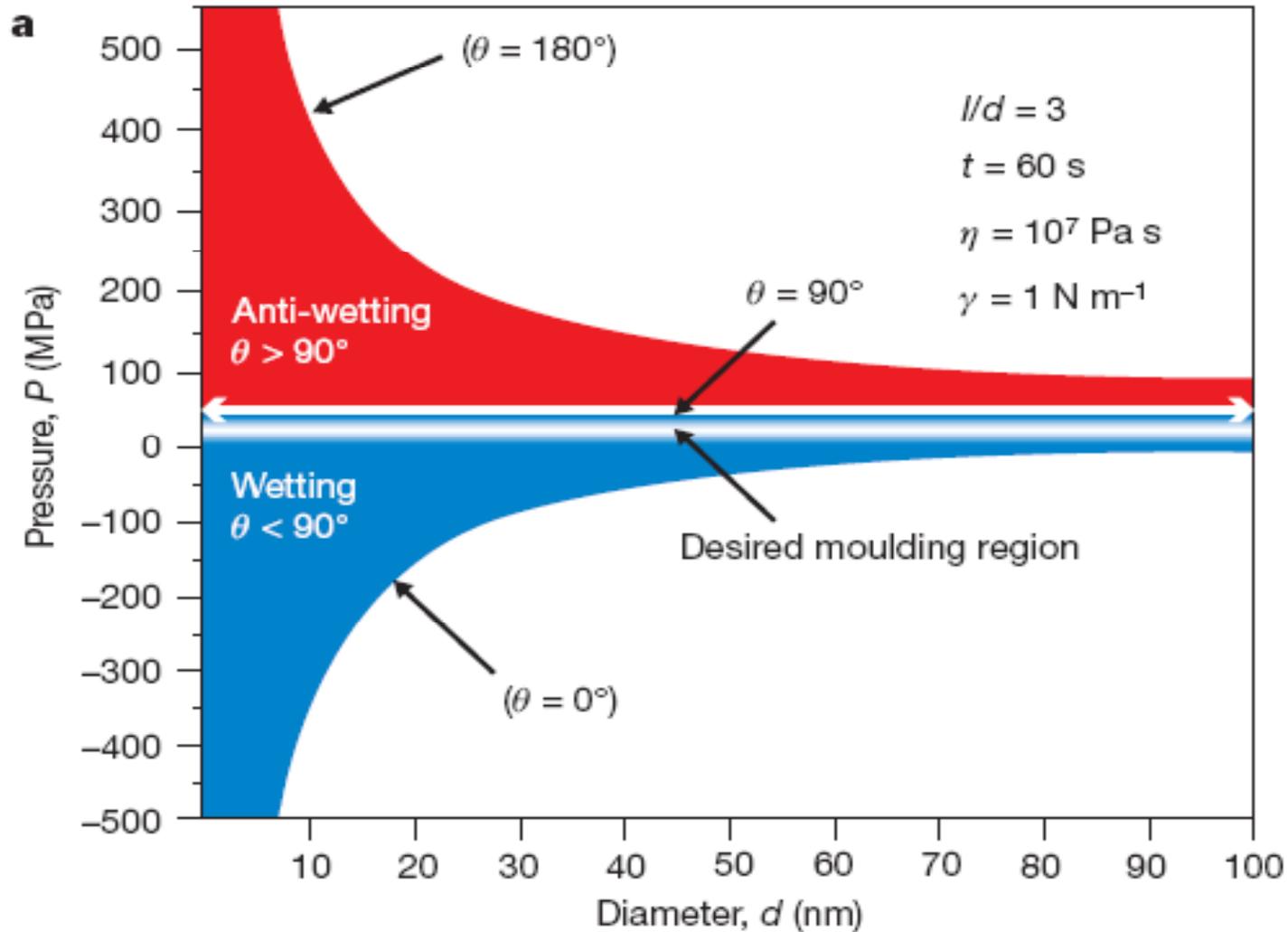
*C. Torres, Editor, *Alternative Lithography: Unleashing the Potentials of Nanotechnology*, Kluwer, 2003

Flow in a channel

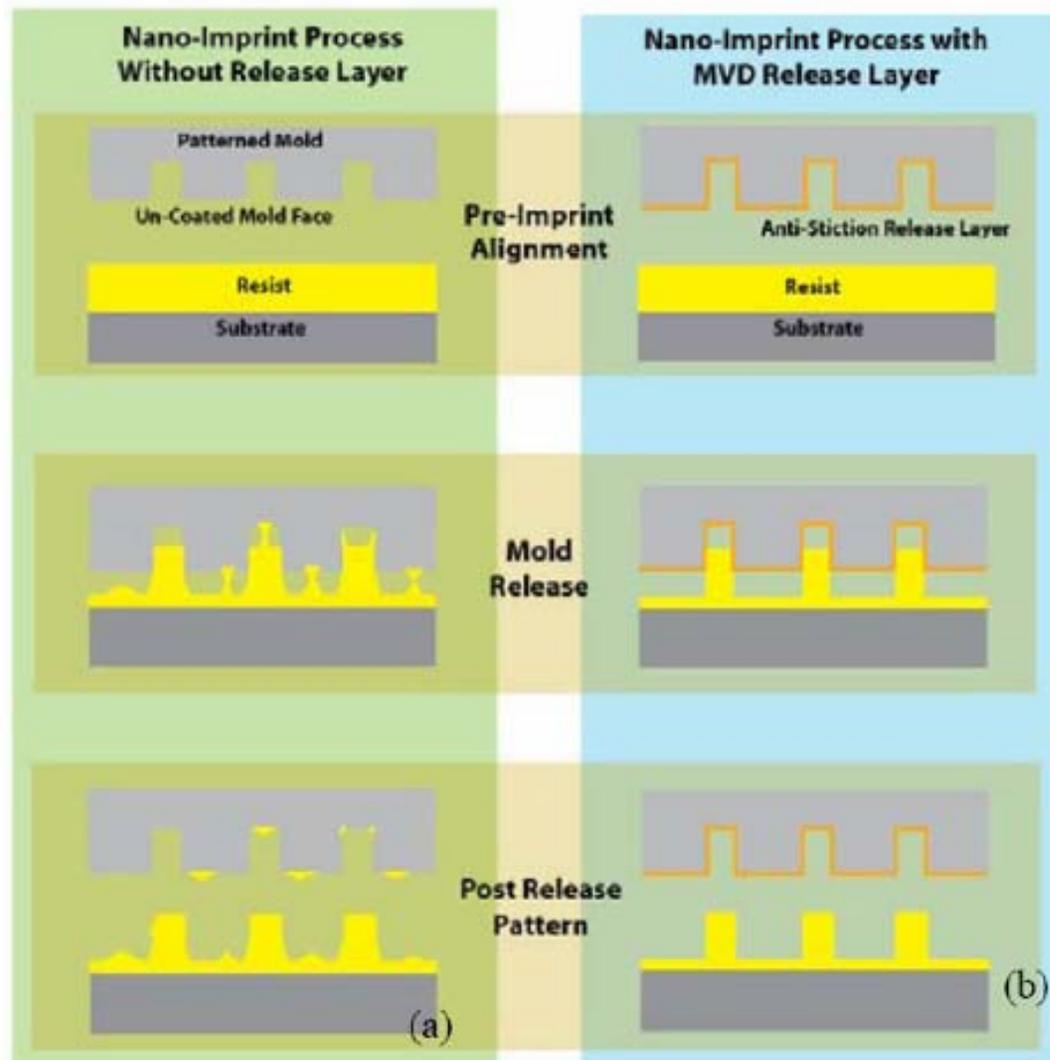


$$P = \frac{32\eta}{t} \left(\frac{l}{d} \right)^2 - \frac{4\gamma \cos \theta}{d}$$

Molding pressure for filling a channels

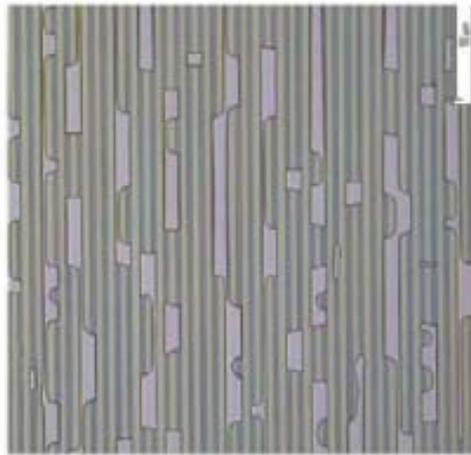


Importance of Antistick

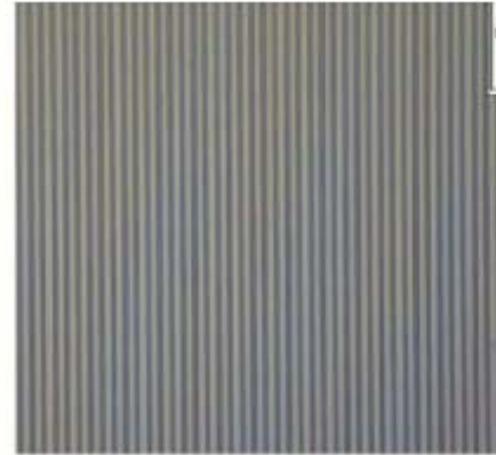


T. Zhang et al., SPIE 2006

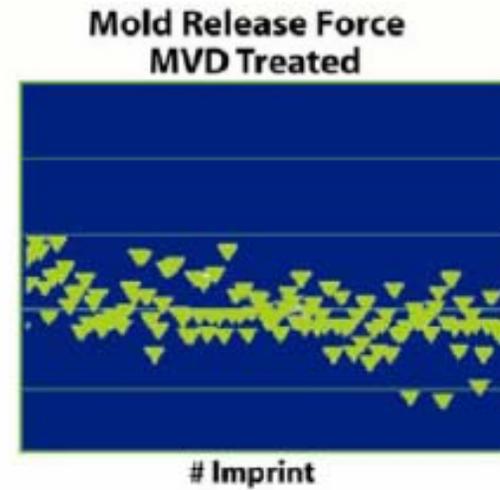
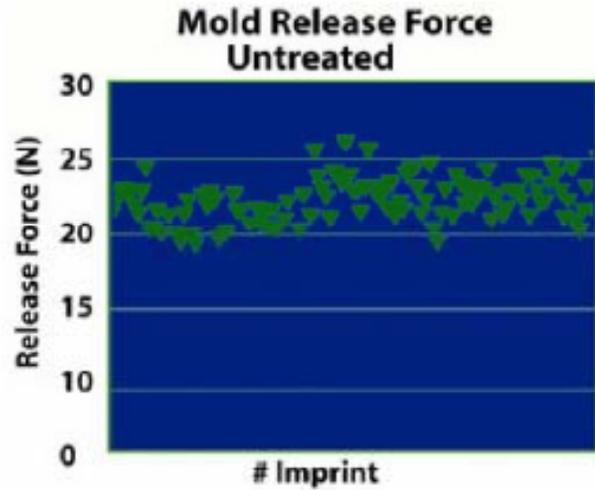
NIL with and without Antistick



Line Imprint of Untreated Mold



Line Imprint of MVD Treated Mold



Resist Issues

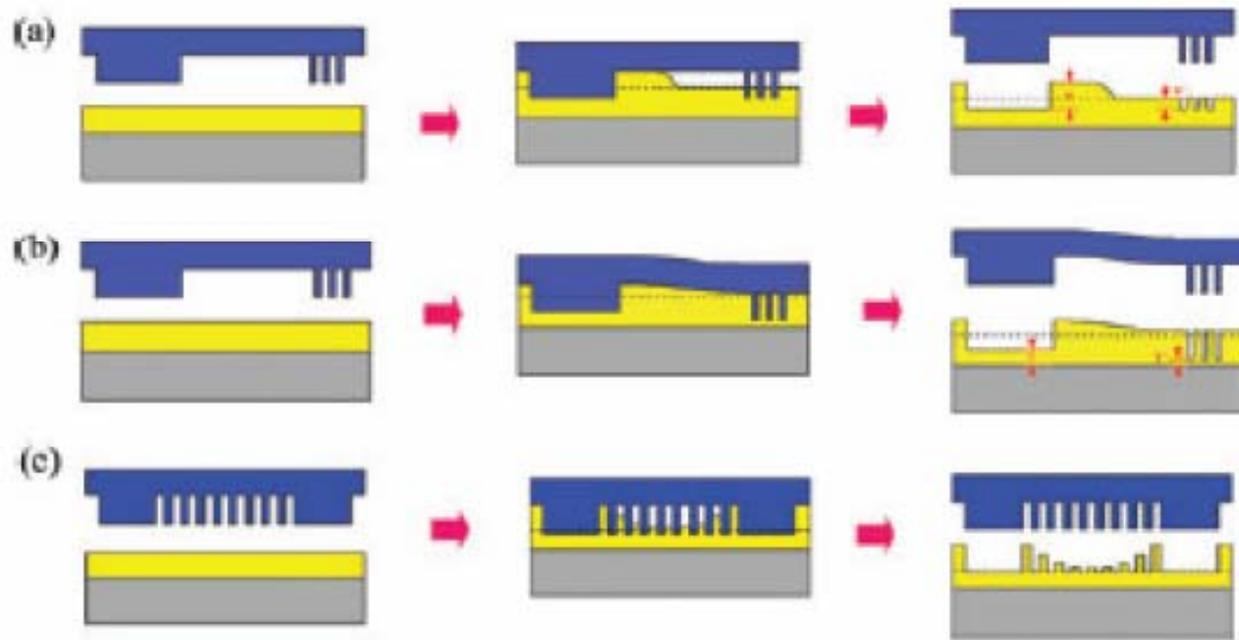
- Proper glass transitional temperature
- Minimal shrinkage
- Mechanical strength
- Mold fill
- Viscosity

If glass transitional temperature is too low, what will happen?

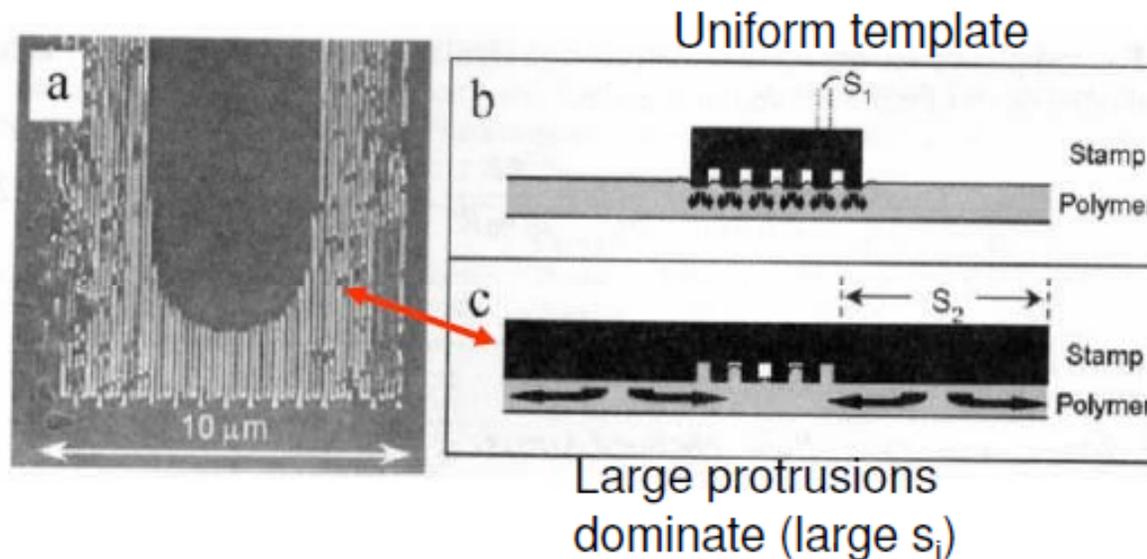


10 days after imprinting a low Tg resist

Issues with Imprinting Micro & Nano Features

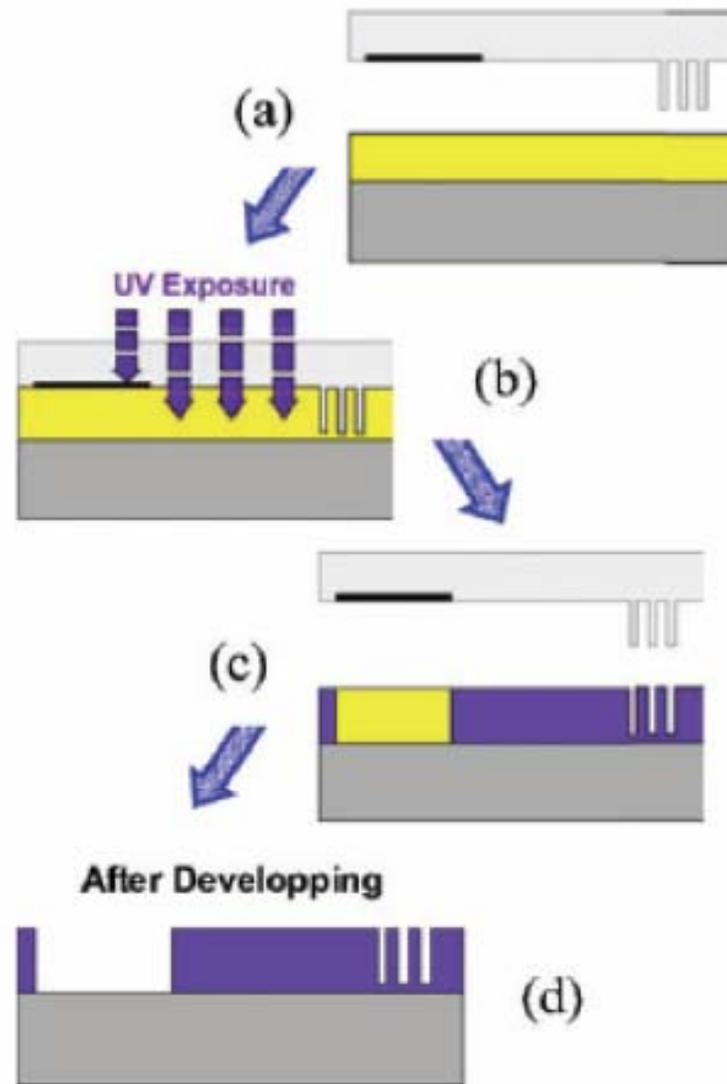


Issues with Imprinting Micro & Nano Features

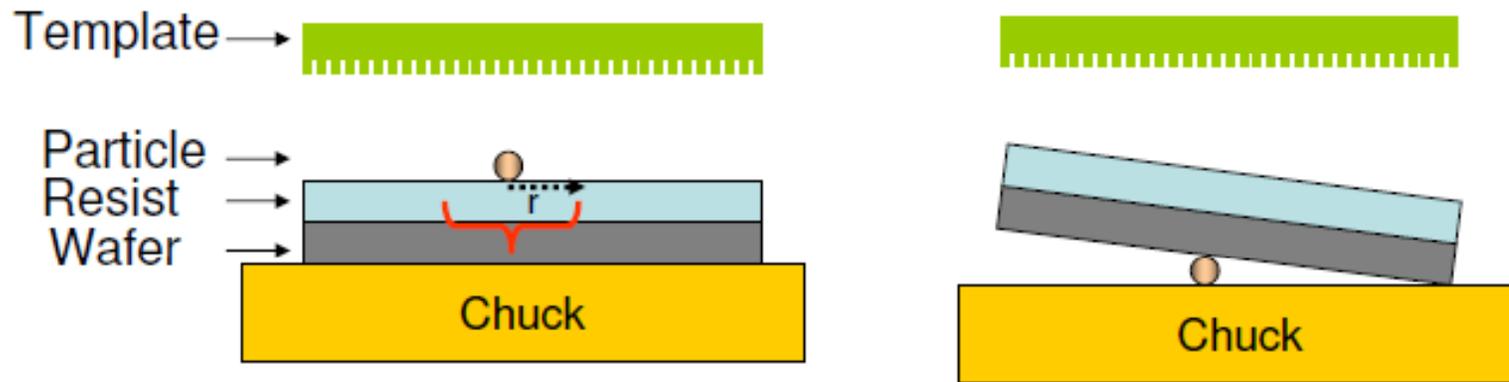


- The fill factor should be kept constant: better flow and shorter imprint time
 - Fabricate dummy cavities/protrusions
- Different fill factor across template leads to different sinking rates
 - template bending → non-uniform residual layer on substrate

Combined UV {for Micro} and Imprint {for Nano}



Imprinting in Presence of a Particle (Contamination)



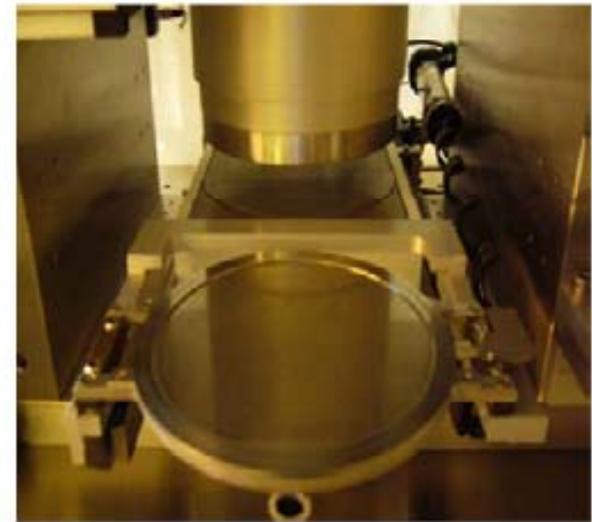
- VERY important to perform imprint in clean environment

NIL System Overview

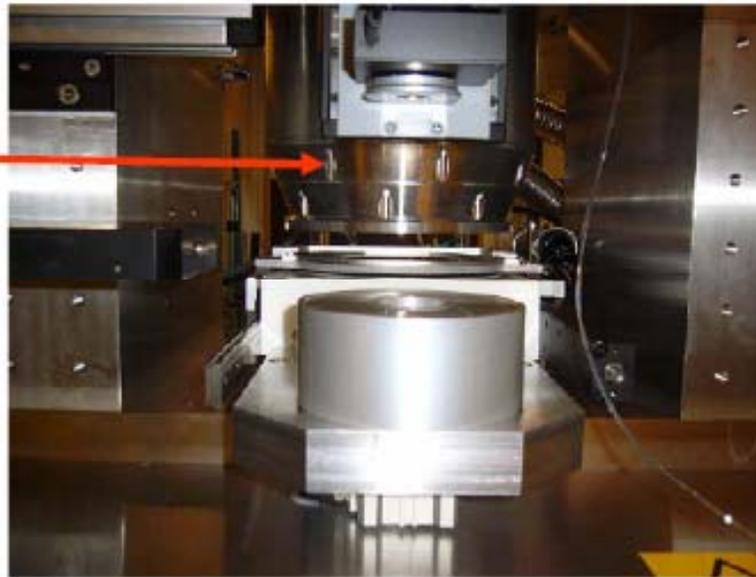


- Obducat (Sweden based)
- 6" max wafer size
- Max temp: 300°C
- Max pressure: 70 bar
- UV module: 365 nm (filter)
- Integrated alignment: ~1µm (~0.5µm @ tool demo)
- Automatic demolding
- Easy software interface
- Start-to-finish: fully automatic or semiautomatic (up to user)

Loader & Front View of System



UV module



Main Operating Window in Software

The screenshot displays the 'NIL System Control' software interface. At the top, the title bar reads 'Nanoprinter System Control'. The main window title is 'NIL System Control', with 'Release version 5.3.0' and the website 'www.obducat.com' on the right. A navigation menu includes 'Inprint', 'Alignment', 'Recipe', 'System', and 'Maintenance'. The 'Inprint' tab is active, showing a control panel on the left and two data plots on the right.

Control Panel (Left):

- Inprint:**
- Hood:**
- Substrate Loader:**
 -
 -
 -
 -
- Inprint Settings:**
 - Inprint Temp. Setpoint (C):
 - Pressure setpoint (bar):
 - Inprint Time (s):
 - Release Temperature (C):
 - Work Temperature (C):
 - UV Lamp (On / Off):
- Currently Loaded Recipe:**
- Current Inprint Step:**
- Profile Chart Filename:**

Data Plots (Right):

- Temp. (X=Time, Y=Temp):** Temperature (C)
UV(DryOff)
- Pressure (X=Time, Y=Pressure):** Current Pressure (bar)

Status Bar (Bottom):

- Status:
- Error:
- Emergency stop:
- Hood Sensor:
- Standby:
- State:

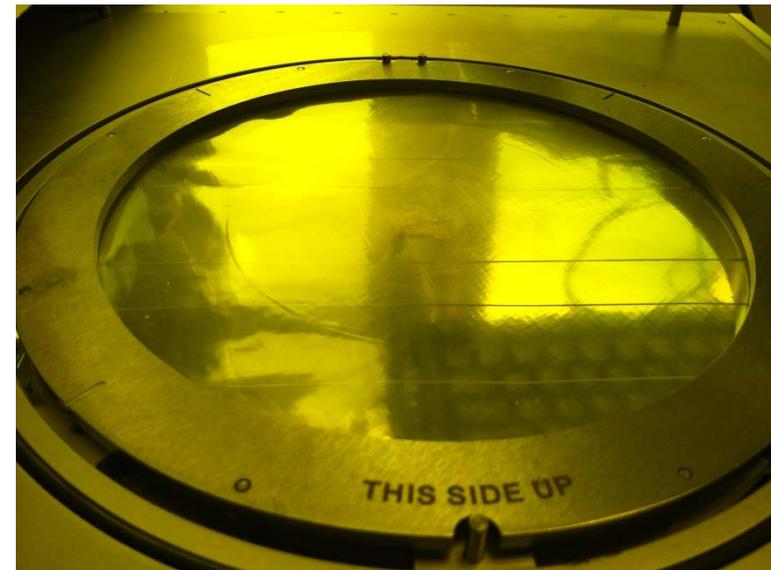
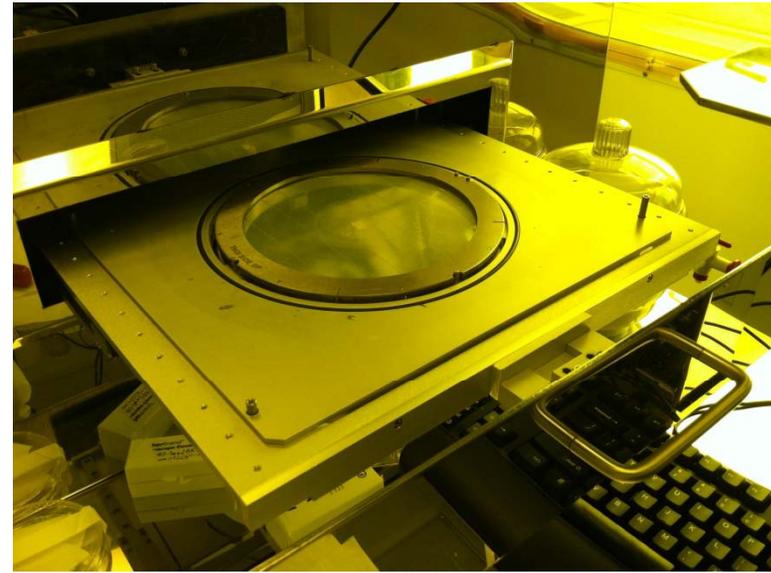
NIL System Overview

NX-2600/2600BA, Full-Wafer Imprinter with Alignment and Photolithography

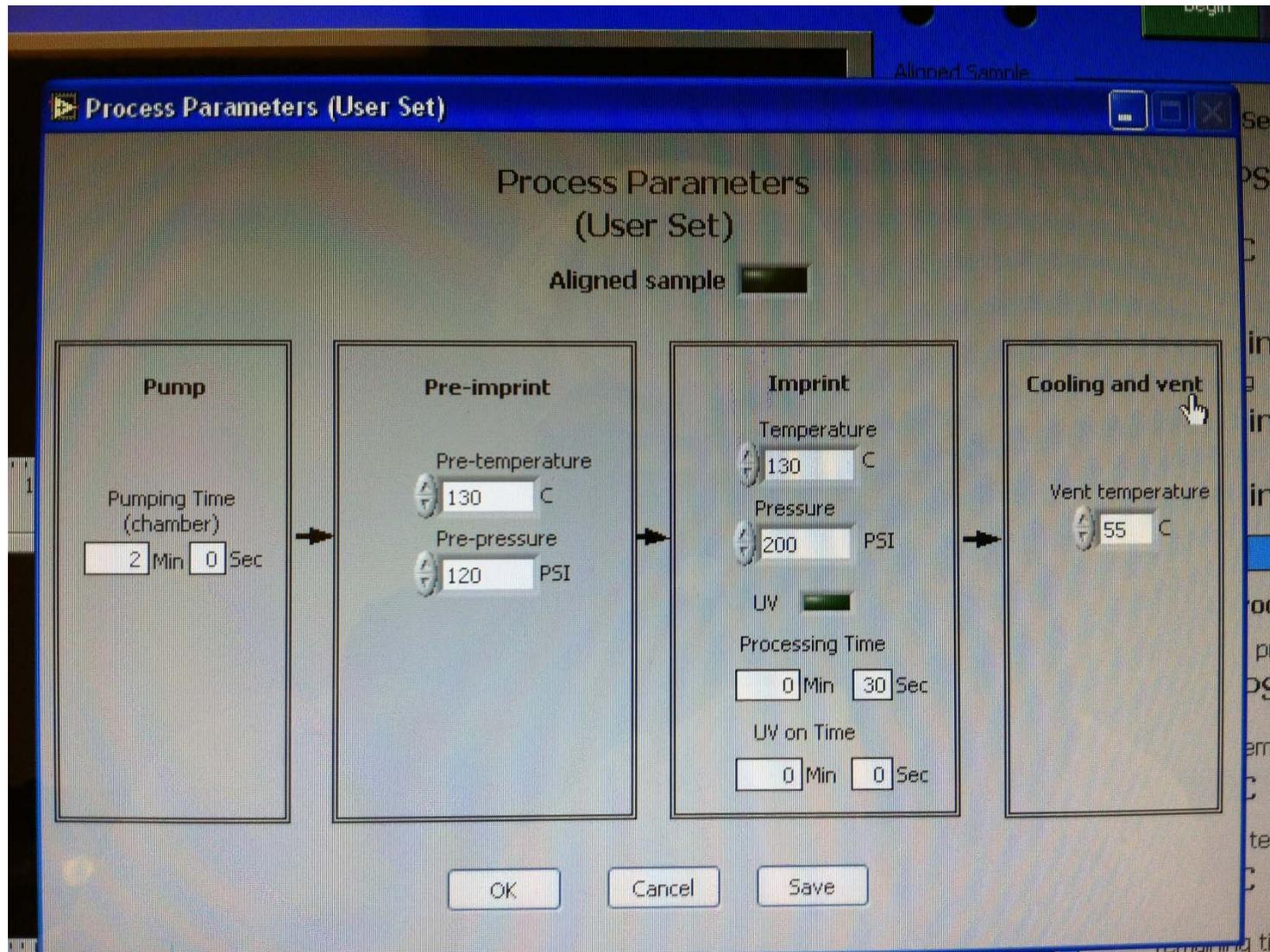


- Full-wafer (up to 8") nanoimprinting tool
- All forms of nanoimprint and high resolution photolithography
- Patented Air Cushion Press™ (ACP) for ultimate nanoimprint uniformity
- Sub-micron overlay alignment accuracy and optical backside alignment (NX-2600BA)
- User friendly alignment scheme
- Smart Sample Holder for handling different sizes and irregular shapes
- Applications in opto, displays, biotechnologies, data storage, materials, ..., etc

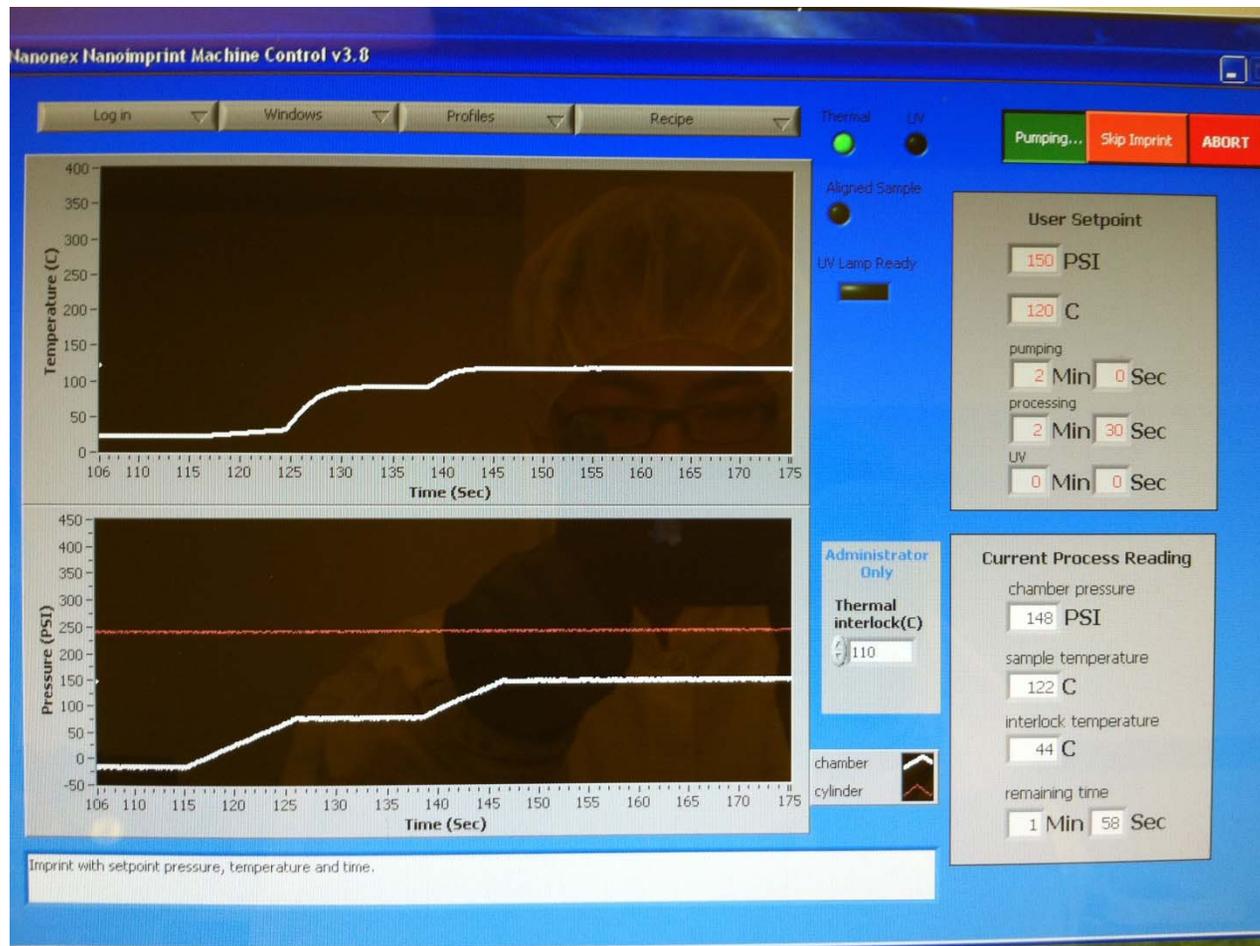
Nanonex 2600



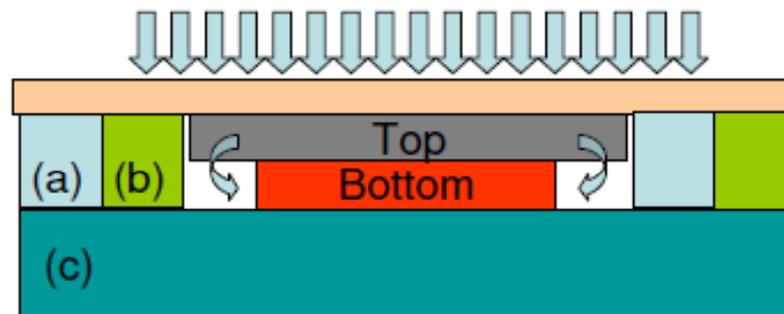
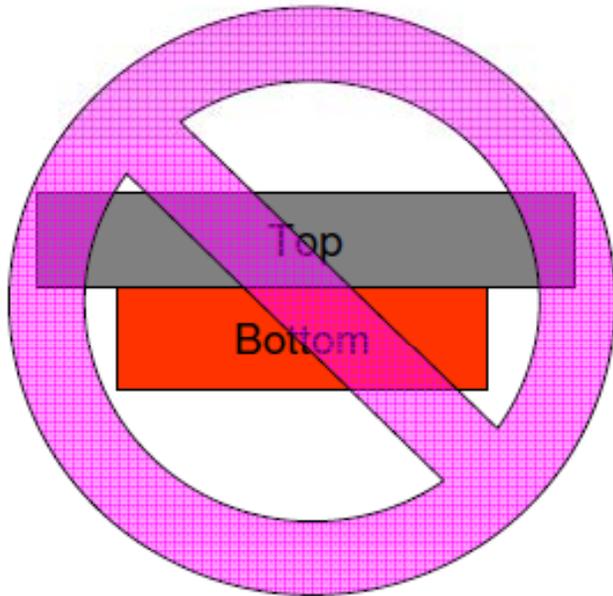
Nanonex 2600 software



Nanonex 2600



Relative Size of Top & Bottom Substrates



Conclusion

There are major differences between soft-litho & nanoimprint-litho & photolithography:

- Soft template vs. hard template
- The resist used
- Resolution and application

Umass Lowell offer:

- Soft-litho
- Photolithography
- Nanoimprint-litho: Thermal & UV